**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a TO220F "full pack" plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/dt can occur. This "series CT" triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)}$  = 150 °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- · High immunity to false turn-on by dV/dt
- · High voltage capability
- Isolated mounting base package
- Less sensitive gate for very high noise immunity
- · Planar passivated for voltage ruggedness and reliability
- · Triggering in three quadrants only

## 3. Applications

- Applications subject to high temperature (T<sub>j(max)</sub> = 150 °C)
- Electronic thermostats (heating and cooling)
- · High power motor controls e.g. washing machines and vacuum cleaners
- · Rectifier-fed DC inductive loads e.g. DC motors and solenoids

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>h</sub> ≤ 84°C; Fig.1; Fig. 2; Fig. 3	12	A
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ =20ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	100	A
		full sine wave; t <sub>p</sub> =16.7ms; T <sub>j(init)</sub> = 25 °C	110	Α
T <sub>j</sub>	junction temperature		150	°C

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;}$ $T_j = 25 \text{ °C; } Fig. 7$	2	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;}$ $T_j = 25 ^{\circ}\text{C; } Fig. 7$	2	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	2	-	35	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	35	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 15 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
Dynamic	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	300	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_{DM}$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/µs; gate open circuit; snubberless condition	20	-	-	A/ms

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	<b>N</b> 1
2	T2	main terminal 2		T2—T1
3	G	gate		sym051
mb	n.c.	mounting base; isolated		

# 6. Ordering information

Table 3. Ordering information

Table 3. Ordering information							
Type number	Package	Orderable part number	Packing	Small packing	Package	Package	
	Name		method	quantity	version	issue date	
BTA312X-800CT	TO220F	BTA312X-800CTQ	Tube	50	SOT186A	14-Nov-2013	
BTA312X-800CT/L01	TO220F	BTA312X-800CT/L01Q	Tube	50	SOT186A/L01	14-Nov-2013	

# 7. Marking

#### Table 4. Marking codes

Table is married oction	
Type number	Marking codes
BTA312X-800CT	BTA312X 800CT

BTA312X-800CT

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# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>mb</sub> ≤ 84°C; Fig. 1; Fig. 2; Fig. 3	12	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	100	А
		full sine wave; $t_p$ = 16.7 ms; $T_{j(init)}$ = 25 °C	110	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>P</sub> = 10 ms; sine wave pulse	50	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 70 mA	100	A/µs
I <sub>GM</sub>	peak gate current		2	А
$P_{GM}$	peak gate power		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.5	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

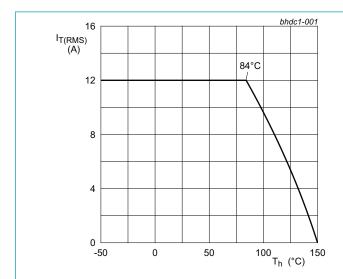
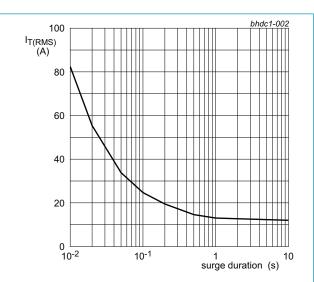
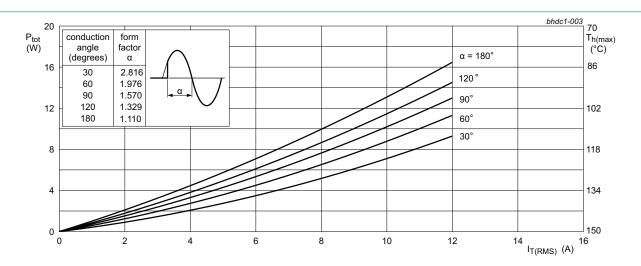


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_h = 84 ^{\circ}\text{C}$ 

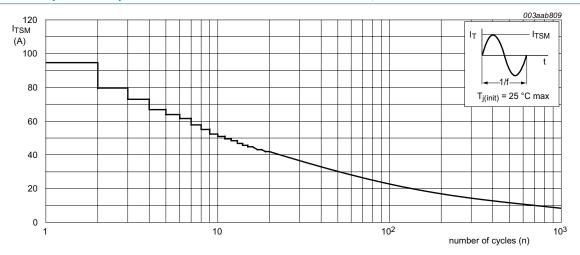
Fig. 2. RMS on-state current as a function of surge duration; maximum values



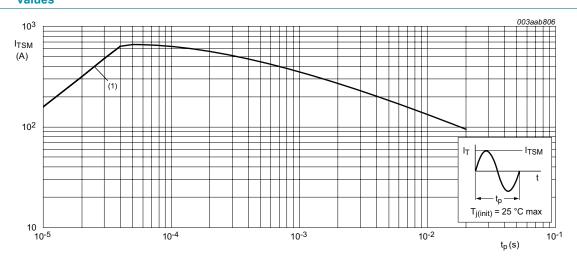
a = form factor =  $I_{T(RMS)} / I_{T(AV)}$ 

 $\alpha$  = conduction angle

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



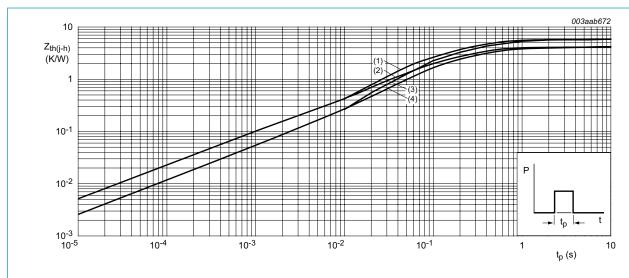
 $t_p \le 20 \text{ ms}$ (1)  $dI_T/dt \text{ limit}$ 

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-h)</sub>	thermal resistance	with heatsink compound; Fig. 6	-	-	4	K/W
	from junction to heatsink	without heatsink compound; Fig. 6	-	-	5.5	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	-	5	-	K/W



- (1) Unidirectional (half cycle) without heatsink compound
- (2) Unidirectional (half cycle) with heatsink compound
- (3) Bidirectional (full cycle) without heatsink compound
- (4) Bidirectional (full cycle) with heatsink compound

Fig. 6. Transient thermal impedance from junction to heatsink as a function of pulse duration

### 10. Isolation characteristics

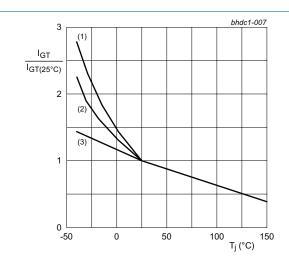
**Table 7. Isolation Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS)</sub>	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C <sub>isol</sub>	isolation capacitance	from cathode to external heatsink	-	10	-	pF

## 11. Characteristics

#### **Table 8. Characteristics**

<b>Symbol</b>	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+; $ $T_j = 25 \text{ °C}; Fig. 7$	2	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;} $ $T_j = 25 \text{ °C; } Fig. 7$	2	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2\text{- G-;} $ $T_j = 25 \text{ °C; } Fig. 7$	2	-	35	mA
I <sub>L</sub>	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G+};$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	50	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	60	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	50	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	35	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 15A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
V <sub>GT</sub> gate tr	gate trigger voltage	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 25 °C Fig. 11	-	0.8	1	V
		V <sub>D</sub> = 400V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 150 °C	0.25	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μΑ
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	1	mA
Dynamic	characteristics		'			
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	300	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 12 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	20	-	-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

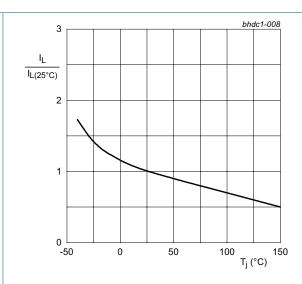


Fig. 8. Normalized latching current as a function of junction temperature

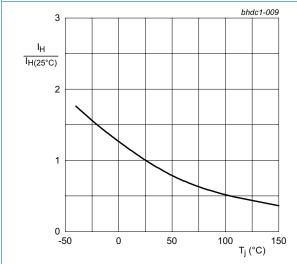
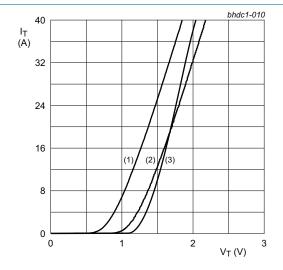


Fig. 9. Normalized holding current as a function of junction temperature



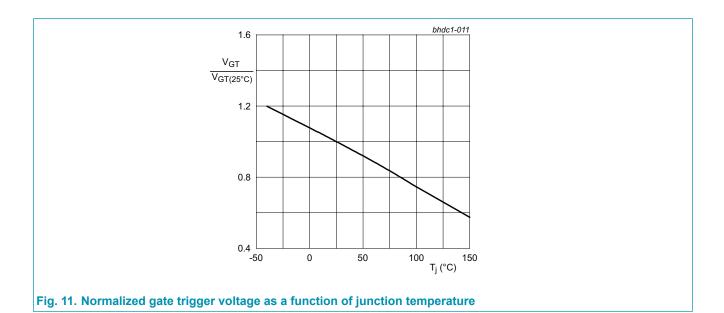
 $V_o = 1.097 \text{ V}; R_s = 0.0321 \Omega$ 

(1) T<sub>i</sub> = 150 °C; typical values

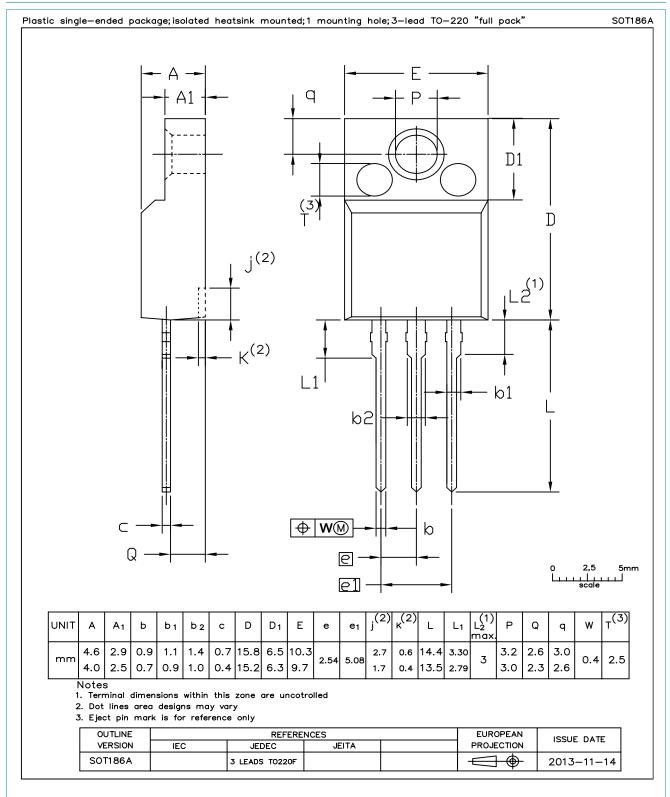
(2) T<sub>i</sub> = 150 °C; maximum values

(3)  $T_j = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



# 12. Package outline



## 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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**Product data sheet** 

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For more information, please visit: http://www.ween-semi.com
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